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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/611,334	HECK ET AL.	
Examiner	Art Unit	
Hsien-ming Lee	2823	

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SEARCHED				
Class	Subclass	Date	Examiner	
438	25,51	3/2/2007	LEE	
438	106-108	3/2/2007	reė	
438	113	3/2/2007	LEE	
257	414,678	3/2/2007	LEE	
257	684,704	3/2/2007	LEE	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	2/27/2007	LEE
EAST attached (USPAT, USPG)	3/2/2007	LEE